Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/748,298	HAZUCHA ET AL.
Examiner	Art Unit
Linh M. Nauven	2816

SEARCHED					
Class	Subclass	Date	Examiner		
327	172	12/23/05	LAN		
Ч	175	(1	q		
ų	176	u u	Ŋ		
а	263	4	4		
Ч	276	ч	4		
4	284	4	q		
4	29/	۹ .	4		
۲	294 299	4	c)		
٧/	299	(,	7		
	•				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
		,		